#### 软件启动

- 1. 进入 Xmanager->选择 njupt01->username:选择 eda1-eda45 其中一个->password: 1->password for root: njupt
- 2. 右键 open in terminal
- 3. 输入: cd DFTC1\_2013.03/lab7\_topdown
- 4. 输入: source /home/eda/bashrc

#### Scan 流程

Scan 流程如下: 以 top down 流程为例

Scan 部分

注意下划线,空格和斜杠,需严格按照示例输入

1、启动 dc 工具

[wangyb@server01 lab7\_topdown]\$ dc\_shell | tee topdown0401.log

Design Compiler Graphical
DC Ultra (TM)
DFTMAX (TM)
Power Compiler (TM)
DesignWare (R)
DC Expert (TM)
Design Vision (TM)
HDL Compiler (TM)
VHDL Compiler (TM)
DFT Compiler
Design Compiler(R)

Version K-2015.06-SP5-2 for linux64 - Apr 11, 2016

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or distribution of this software is strictly prohibited.
Initializing...

注释: tee 是将所有的命令显示出来,放到 topdown0401.log 文件中,其中.log 为后缀,前面为文件名,可随意取。

# 2、读取设计文件

```
dc_shell> read_ddc mapped/ORCA.ddc
Loading db file '/home/pktt/wangyb/njupt/DFTC1_2013.03/ref/db/sc_max.db'
Loading db file '/home/pktt/wangyb/njupt/DFTC1_2013.03/ref/db/io_max.db'
Loading db file '/home/pktt/wangyb/njupt/DFTC1_2013.03/ref/db/rams_max.db'
Loading db file '/home/pktt/wangyb/njupt/DFTC1_2013.03/ref/db/rams_max.db'
Loading db file '/usr/eda/synopsys/syn_K201506SP5_2/libraries/syn/dw_foundation.sldb'
Loading db file '/usr/eda/synopsys/syn_K201506SP5_2/libraries/syn/gtech.db'
Loading db file '/usr/eda/synopsys/syn_K201506SP5_2/libraries/syn/gtech.db'
Loading link library 'cb13fs120_tsmc_max'
Loading link library 'cb13io320_tsmc_max'
Loading link library 'cb13 tsmc_memory_max'
Loading link library 'cb13 tsmc_memory_max'
Loading link library 'cb13special'
Loading link library 'gtech'
Reading ddc file '/home/pktt/wangyb/njupt/DFTC1_2013.03/lab7_topdown/mapped/ORCA.ddc'.
Information: Checking out the license 'DesignWare'. (SEC-104)
Loaded 16 designs.
Current design is 'ORCA'.
ORCA CLOCK_GEN ORCA_TOP_RESET_BLOCK_PCI_CORE_PARSER_CONTEXT_MEM_RISC_CORE_BLENDER_SDRAM_IF_PCI_RFIFO
```

注释: 出现 dc\_shell 标志成功启动工具,读取 ddc 文件,ddc 文件是 neltist 文件+constraint 文件,前期保存而来,所以会自动显示 current design,如果单独读入 netlist 文件需要设计 current design 和 link 命令。

```
dc shell> set current design ORCA
ORCA
dc_shell> link
 Linking design 'ORCA'
 Using the following designs and libraries:
            /home/pktt/liuxt/lxt/ces_dftc1 2013.03/DFTC1 2013.
 * (16 designs)
03/lab7 topdown/mapped/ORCA.ddc, etc
 cbl3fs120 tsmc max (library) /home/pktt/liuxt/lxt/ces dftc1_2013.03/DFTC1_2013
.03/ref/db/sc max.db
 cb13io320 tsmc max (library) /home/pktt/liuxt/lxt/ces dftc1 2013.03/DFTC1 2013
.03/ref/db/io max.db
 cb13 tsmc memory max (library) /home/pktt/liuxt/lxt/ces dftc1 2013.03/DFTC1 20
13.03/ref/db/rams max.db
 cb13special (library)
                           /home/pktt/liuxt/lxt/ces dftc1 2013.03/DFTC1 2013.
03/ref/db/special.db
 dw foundation.sldb (library) /usr/eda/synopsys/syn 0-2018.06-SP5-1/libraries/s
yn/dw foundation.sldb
-
J- -b-11: --+ +--+ J-f-::1+ J-1-:: A
```

注释: link 意义在于是否设计文件所需要的 cell 和库相对应,相对应则为 1,不对应则为 0。

#### 3 setup timing

```
c_shell> set test_default_dalay 0
dc_shell> set test_default_bidir_delay 0
dc_shell> set test_default_strobe 40
```

注释: 这步骤的设定,可以在 command mode 中指定,也可以写在 synopsys\_dc.setup 档中.主要是在设定将来 ATE 使用时,Timing 的规范.

## 4、设置 dft 信号

```
dc_shell> set_dft_signal -view existing_dft -type ScanClock -timing {45 55} -port {pclk sdr_clk sys_clk}

Accepted dft signal specification for modes: all_dft

dc_shell> set_dft_signal -view existing_dft -port prst_n -type Reset -active_state 0

Accepted dft signal specification for modes: all_dft

dc_shell> set_dft_signal -view existing_dft -port scan_en -type ScanEnable -active_state 1

Accepted dft signal specification for modes: all_dft

dc_shell> set_dft_signal -view existing_dft -type Constant -active_state 1 -port test_mode

Accepted dft signal specification for modes: all_dft

1

dc_shell> =
```

注释: set dft signal 是用来指定输入输出端口为 DFT 信号。

- view 有两种类型,一种是 existing\_dft,一种是 spec。所谓 existing\_dft,就是告诉工具,这个 port 已经被用作某种类型的 DFT 信号了,此时扫描链已经插入了。所谓 spec,就是告诉工具,下面指定的 port 将被用做某种类型的 DFT 信号。
- type 是用于指定 DFT 信号的类型,包括
  Reset,Constant,TestMode,TestData,ScanDataIn,ScanDataOut,ScanMa
  sterClock,ScanSlaveClock 等。

- port 是用于指定规则适用的端口。
- active\_state 用于指定 Reset, ScanEnable, TestMode, Constant 是高电平有效,还是低电平有效。

这里 timing 设置将 port 端口 pclk、sdr\_clk.sys\_clk 设置为 ScanClock 模式,因为 timing 在设置 dft 已经存在,所以设置为 existing 模式,并且在 45 时刻上升,55 时刻下降。

### 5、创建测试协议

```
dc_shell> create_test_protocol
In mode: all_dft...

Information: Starting test protocol creation. (TEST-219)
    ...reading user specified clock signals...
Information: Identified system/test clock port sys_clk (45.0,55.0). (TEST-265)
Information: Identified system/test clock port pclk (45.0,55.0). (TEST-265)
Information: Identified system/test clock port sdr_clk (45.0,55.0). (TEST-265)
    ...reading user specified asynchronous signals...
Information: Identified active low asynchronous control port prst_n. (TEST-266)
```

注释:功能:根据当前设计指定的规则,比如 set\_dft\_signal, set\_sc an\_path, set\_scan\_configuration来创建测试协议。

# 6、drc 规则检查

```
dc_shell dft_drc
In mode: all dft...

Pre-DFT DRC enabled
Warning: Design 'ORCA' contains 3 high-fanout nets. A fanout number of 1000 will be used for delay calculations involving these nets. (TIM-134)
Warning: A non-unate path in clock network for clock 'SDRAM_CLK'
from pin 'I_ORCA TOP/I_SDRAM_IF/Sd mux_dq out 0/Z' is detected. (TIM-052)
Warning: Gated clock latch is not created for cell 'I_CLOCK GEN/U5'on pin '10' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_PCI_READ_IFO/PCI_RETIO_RAM'on pin '0E1' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_PCI_READ_IFO/PCI_WEITE RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_PCI_WRITE_FIFO/PCI_WFIFO_RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_SDRAM_READ_FIFO/SD_REIFO_RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_SDRAM_READ_FIFO/SD_WFIFO_RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_SDRAM_WEITE FIFO/SD_WFIFO_RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: Gated clock latch is not created for cell 'I_ORCA TOP/I_SDRAM_WEITE FIFO/SD_WFIFO_RAM'on pin 'CE2' in design 'ORCA'. (TIM-141)
Warning: A non-unate path in clock network for clock 'SDRAM_CLK'
```

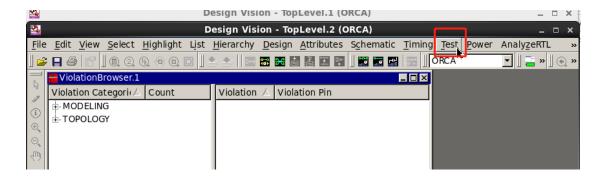
注释:这个是插入扫描链之前的规则检查,即对先前指定的规则检查。

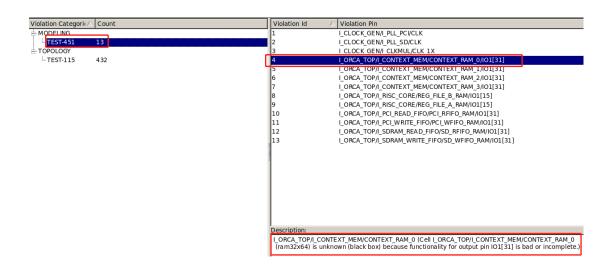
### 可以利用 gui 界面进行查看设计规则

## 6.1、启动 gui 界面

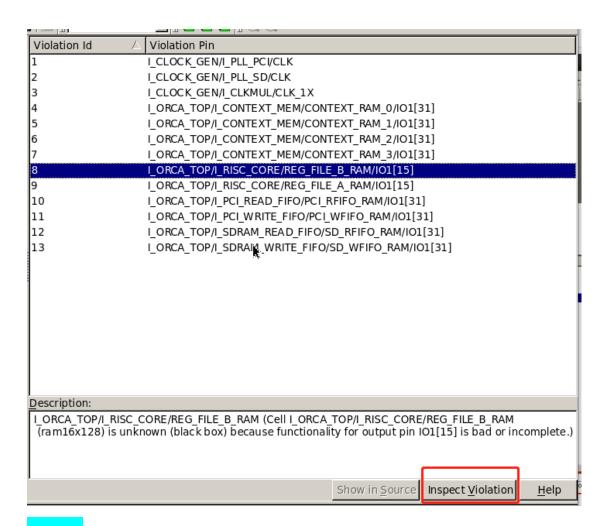
```
dc_shell> start_gui
dc_shell> current design is 'ORCA'.
4.1
Current design is 'ORCA'.
dc_shell> ■
```

#### 6.2 Test/Run DFT DRC





**注释**: 可以查看每个规则检查,基础学习主要修复时钟,复位是否可控。



注释: 可以利用电路界面进行查看 violation

drc 结果

```
DRC Report
 Total violations: 445
_____
13 MODELING VIOLATIONS
   13 Cell has unknown model violations (TEST-451)
432 TOPOLOGY VIOLATIONS
  432 Improperly driven three-state net violations (TEST-115)
Warning: Violations occurred during test design rule checking. (TEST-124)
 Sequential Cell Report
 32 out of 2958 sequential cells have violations
SEQUENTIAL CELLS WITH VIOLATIONS
     * 32 cells have test design rule violations
SEQUENTIAL CELLS WITHOUT VIOLATIONS
     *2926 cells are valid scan cells
Information: Test design rule checking completed. (TEST-123)
Current design is 'ORCA'.
Current design is 'ORCA'.
1
```

# 7、查看 scan 状态

#### dc\_shell> report\_dft\_signal

\*

Report : DFT signals

Design : ORCA

Version: K-2015.06-SP5-2

Date : Thu Apr 1 15:24:23 2021

TEST MODE: all\_dft
VIEW : Specification

\_\_\_\_\_

No DFT signals defined in this mode.

ŧ

\*\*\*\*\*\*\*\*\*\*\*\*\*\*

Report : DFT signals

Design : ORCA

Version: K-2015.06-SP5-2

Date : Thu Apr 1 15:24:23 2021

\*\*\*\*\*\*\*\*\*\*\*\*\*

TEST MODE: all\_dft VIEW : Existing DFT

Port	SignalType	Active	Hookup	Timing	Usage
test mode	Constant	1	-		
scan en	ScanEnable	1	-		
sys clk	ScanMasterClock	1	-	P 100.0 R	45.0 F 55.0
sys clk	MasterClock	1	-	P 100.0 R	45.0 F 55.0
sdr clk	ScanMasterClock	1	-	P 100.0 R	45.0 F 55.0
sdr_clk	MasterClock	1	-	P 100.0 R	45.0 F 55.0
pclk	ScanMasterClock	1	-	P 100.0 R	45.0 F 55.0
pclk	MasterClock	1	-	P 100.0 R	45.0 F 55.0
prst n	Reset	Θ	-	P 100.0 R	55.0 F 45.0

## 8、设置扫描链配置

```
dc_shell> set_scan_configuration -chain_count 6 -add_lockup true -clock_mixing mix_clocks
Accepted scan configuration for modes: all_dft
```

注释: 利用 set\_scan\_configuration 来对全局的 scan chain 进行配置。比如扫描链的类型,长度,个数等等信息。需要特别注意的是多时钟的构建,DFT 在默认的时候是为每个时钟域创建一个 scan chain,使用 set\_scan\_configuration -clock\_mixing mixing\_clocks 就允许多个时钟域的信号位于同一个扫描链上。当有不同的时钟串在一起,将会加入 lock-up 单元,解决多个时钟串 chain 问题。

## 9、对每条扫描链输入输出端口设置

ior {set i 0} {\$i < 6} {incr i} {
 set hookup cell pad iopad \$i</pre>

```
set_dft_signal -view spec -port pad[$i] -type ScanDataIn -hookup pin $hookup cell/CIN
   set hookup cell sdram A iopad $i
   set_dft_signal -view spec -port sd_A[$i] -type ScanDataOut -hookup_pin $hookup_cell/I
   set scan path chain$i -view spec -scan data in pad[$i] -scan data out sd A[$i]
dc_shell> source ./scripts/settings_insert_dft.tcl
Accreted scan configuration for modes: all dft
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain0' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain2' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain3' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain4' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
Accepted dft signal specification for modes: all dft
Accepted dft signal specification for modes: all dft
Warning: Scan chain 'chain5' overwrites an earlier specification. (TESTDB-255)
Accepted scan path specification for mode: Internal scan
```

<mark>注释:</mark> 其中每个 scan input 和 scan output 都使用了 hookup pin 连接。

10 preview\_dft

```
epieu <u>scan pain speciiicacion foi moue.</u> incernac scan
dc[shell> preview dft -show scan summary
Warning: The cache_read directory ../dc_dw_cache is not readable. (SYNOPT-10)
Warning: The cache write directory ../dc dw cache is not writable. So no cache elements car
Warning: Design 'ORCA' contains 3 high-fanout nets. A fanout number of 1000 will be used fα
Warning: A non-unate path in clock network for clock 'SDRAM CLK'
from pin 'I_ORCA_TOP/I_SDRAM_IF/sd_mux_dq_out_0/Z' is detected. (TIM-052)
Warning: Gated clock latch is not created for cell 'I_CLOCK_GEN/U5'on pin 'I0' in design '(
Warning: Gated clock latch is not created for cell 'I ORCA TOP/I RISC CORE/U3'on pin 'B1' i
Warning: Gated clock latch is not created for cell 'I ORCA TOP/I PCI READ FIFO/PCI RFIFO R/
Warning: Gated clock latch is not created for cell 'I_ORCA_TOP/I_PCI_WRITE_FIFO/PCI_WFIFO_F
Warning: Gated clock latch is not created for cell 'I_ORCA_TOP/I_SDRAM_READ_FIFO/SD_RFIFO_F
Warning: Gated clock latch is not created for cell 'I ORCA TOP/I SDRAM WRITE FIFO/SD WFIFO
Warning: Gated clock latch is not created for cell 'I CLOCK GEN/U2'on pin 'A2' in design '(
Warning: A non-unate path in clock network for clock 'SDRAM CLK'
from pin 'I ORCA TOP/I SDRAM IF/sd mux dq out 0/Z' is detected. (TIM-052)
Information: Starting test design rule checking. (TEST-222)
Warning: Violations occurred during test design rule checking. (TEST-124)
Information: Test design rule checking completed. (TEST-123)
  Architecting Scan Chains
```

注释: 在做 inser\_dft 之前查测试点的信息,扫描链的信息。根据这

些信息来确定所加的 dft 规格是否完备。

```
Number of chains: 6
Scan methodology: full scan
Scan style: multiplexed_flip_flop
Clock domain: mix_clocks
Scan enable: scan en (no hookup pin)
Chain
           Scan Ports (si --> so)
                                          # of Cells
                                                       Inst/Chain
                                                                                 Clock (port, time, edge)
                                                       I_ORCA_TOP/I_SDRAM_IF/DQ_out_1_reg_0_
S chain0
           pad[0] --> sd_A[<u>0</u>]
                                                 488
                            (sdr clk
                                             fall<u>ing)</u>
S chain1
           pad[1] --> sd A[1]
                                                 488
                                                       I_ORCA_TOP/I_SDRAM_IF/mega_shift_1_reg_29__8_
                            (sdr_clk, 55.0, falling)
                                                       I ORCA TOP/I BLENDER/latched_clk_en_reg
                                                                                 (sys_clk, 55.0, falling)
                                                       I_ORCA_TOP/I_PARSER/r_pcmd_out_reg_0
                                                                                 (pclk, 45.0, rising)
5 chain2
                                                 488
                                                       I ORCA_TOP/I_PCI_CORE/mega_shift_reg_26__7_
           pad[2] -->
                       sd A[2]
                             (pclk. 45.0. risina
                                                       I ORCA TOP/I PCI_CORE/mega_shift_reg_56__15_
S chain3
           pad[3] -->
                       sd A[3]
                             (pclk, 45.0, rising)
                                                       I ORCA TOP/I RESET BLOCK/sdram rst ff reg
                                                                                 (sdr clk, 45.0, rising)
                                                       I ORCA TOP/I SDRAM_IF/mega_shift_0_reg_20__12_
S chain4
           pad[4] --> sd A[4]
                             (sdr clk, 45.0, rising)
                                                       I_ORCA_TOP/I_BLENDER/rem blue reg
                                                                                 (sys_clk, 45.0, rising)
                                                       I ORCA TOP/I_BLENDER/s4_op1_reg_5_
                                                 487
S chain5
           pad[5] --> sd A[5]
                             (sys clk, 45.0, rising)
```

<mark>注释:</mark>6 条 chain 达到平衡,clock mixing 满足条件。

## 11 insert dft

```
dc shell> insert dft
```

insert dft (注意下划线)

# 12、检查上 chain 后的 DRC 以及查看测试覆盖率

```
dc shell> dft drc -coverage estimate
In mode: Internat scan...
Warning: The cache read directory ../dc dw cache is not readable. (SYNOPT-10)
Warning: The cache write directory ../dc dw cache is not writable. So no cache
 Design has scan chains in this mode
 Design is scan routed
 Post-DFT DRC enabled
Information: Starting test design rule checking. (TEST-222)
 Loading test protocol
 ...basic checks...
 ...basic sequential cell checks...
 ...checking vector rules...
 ...checking clock rules...
 ...checking scan chain rules...
 ...checking scan compression rules...
 ...checking X-state rules...
 ...checking tristate rules...
 ...extracting scan details...
 ...saving simulation value info...
           Pattern Summary Report
 #i\hternal patterns
    Uncollapsed Stuck Fault Summary Report
 fault class
                               code #faults
                                DT 70491
Detected
                                        67
1231
                                PT
Possibly detected
Undetectable
                                UD
                                        3302
ATPG untestable
                                ΑU
Not detected
                                ND
                                         105
                                        75196
 total faults
test coverage
 Information: The test coverage above may be inferior
              than the real test coverage with customized
              protocol and test simulation library.
Current design is 'ORCA'.
Current design is 'ORCA'.
```

13、保存网表文件、ddc 文件、spf 文件

```
dc_shell> change_names -rule verilog -hierarchy
Warning: In the design ORCA_TOP_test_1, net 'ptl_sdram_fb' is connecting multiple ports. (UCN-1)
Warning: In the design ORCA_TOP_test_1, net 'ptl_pci_fb' is connecting multiple ports. (UCN-1)

dc_shell> write -f verilog -h -o ./ORCA_scan.v
Writing verilog fite /home/pktt/tiuxt/txt/ces_dftc1_2013.03/DFTC1_2013.03/lab7_topdown/ORCA_scan.v'.
Warning: Verilog 'assign' or 'tran' statements are written out. (VO-4)

dc_shell> write -format ddc -hierarchy -output ./ORCA_scan.ddc
Writing ddc_file '/ORCA_scan.ddc'

dc_shell> write test_protocol -o ./ORCA.spf
Writing test_protocol file '/home/pktt/tiuxt/txt/ces_dftc1_2013.03/DFTC1_2013.03/lab7_topdown/ORCA.spf' for mode 'Internal_scan'...

dc_shell change_names -rule verilog -hierarchy
Warning: In the design ORCA_TOP_test_1, net 'sdram_clk' is connecting multiple ports. (UCN-1)

Warning: In the design ORCA_TOP_test_1, net 'sdram_clk' is connecting multiple ports. (UCN-1)

### Writing verilog file '/home/pktt/liuxt/txt/ces_dftc1_2013.03/DFTC1_2013.03/lab7_topdown/ORCA_scan.v'.

Warning: Verilog file '/home/pktt/liuxt/txt/ces_dftc1_2013.03/DFTC1_2013.03/lab7_topdown/ORCA_scan.v'.

Warning: Verilog 'assign' or 'tran' statements are written out. (VO-4)
```

注释: 这些文件最好一起保存,保存 netlist 和 spf 文件用于

Tetramax o